

<b>Notice of References Cited</b>	Application/Control No. 10/511,149	Applicant(s)/Patent Under Reexamination HIGASHINO ET AL.	
	Examiner Essama Omgba	Art Unit 3726	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2005/0160863 A1	07-2005	Matsumiya, Takeshi	074/492
*	B	US-2006/0043720 A1	03-2006	Sawada et al.	280/775
*	C	US-2006/0156854 A1	07-2006	Sawada et al.	074/493
*	D	US-5,235,734	08-1993	DuRocher et al.	29/455.1
*	E	US-5,573,606	11-1996	Evans et al.	148/440
*	F	US-5,687,990	11-1997	Uphaus, Ludger	280/775
*	G	US-5,743,150	04-1998	Fevre et al.	74/493
*	H	US-5,992,263	11-1999	Bleuel et al.	74/493
*	I	US-6,629,704 B2	10-2003	Eckhart, Richard J.	280/779
*	J	US-6,647,822 B2	11-2003	Ritchie et al.	74/473.31
*	K	US-6,908,590 B2	06-2005	DasGupta, Rathindra	420/534
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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